

## iT2008

10 MHz – 26.5 GHz High-Power Amplifier

Description	The iT2008 is a broadband GaAs MMIC traveling wave amplifier designed for high output power applications where low-frequency extension capabilities are also required. The iT2008 provides a saturated output power of 1 W up to 7 GHz, greater than 29 dBm up to 15 GHz and greater than 25 dBm at 26.5 GHz. Average gain of 10 dB with flatness of +/-1 dB is provided up to 26.5 GHz. DC power consumption is as low as 3.1 W. Input/output ports are DC coupled.							
Features	<ul> <li>Frequency range: 2 GHz – 26.5 GHz with low-frequency extension capability down to 10 MHz</li> <li>30 dBm nominal Psat (2 GHz – 7 GHz)</li> <li>29 dBm nominal Psat (7 GHz – 15 GHz)</li> <li>&gt;25 dBm nominal Psat at 26.5 GHz</li> <li>10 dB nominal gain with +/-1 dB flatness</li> <li>3.1 W DC power consumption</li> <li>Nominal DC bias conditions: 9 V at 350 mA</li> <li>Full chip passivation for high reliability</li> </ul>							
Absolute Ratings	Symbol V <sub>DD</sub> V <sub>GG1</sub> I <sub>DD</sub> I <sub>GG1</sub> Pin Pdiss_D Tch Tm Tst	Parameters/conditionsPositive supply voltageNegative supply voltagePositive supply currentNegative supply currentRF input powerOCDC power dissipation (no RF)Operating channel temperatureMounting temperature (30 s)Storage temperature	Min. -2	Max 11 0 900 1.8 25 5 150 320 150	V V mA dBn dBn V V C	A A N		
Electrical Characteristics (at 25 °C) 50-ohm system, V <sub>DD</sub> =+9 V, Quiescent current (I <sub>DQ</sub> )=350 mA (*) Low frequency extension available.	Symbol BW S21 S11 S22 S12 Psat	Parameters/conditions         Frequency range*         Small signal gain         Gain flatness         Input return loss         Output return loss         Saturated output power (3 dB gain comprest         2 - 10 GHz         2 - 26.5 GHz         Output power (1 dB gain compression)         2 - 10 GHz         2 - 20 GHz         2 - 20 GHz         2 - 20 GHz	ssion)	Min. 2 8 10 8 30 27.5 26.5 23 27 26	Typ. 10 +/-1 15 12 29.5 28.5 25 29 28	<u>Max.</u> 26.5	Units GHz dB dB dB dB dB dBm dBm dBm dBm dBm	
V		2 - 26.5 GHz		22.5	24.5		dBm	

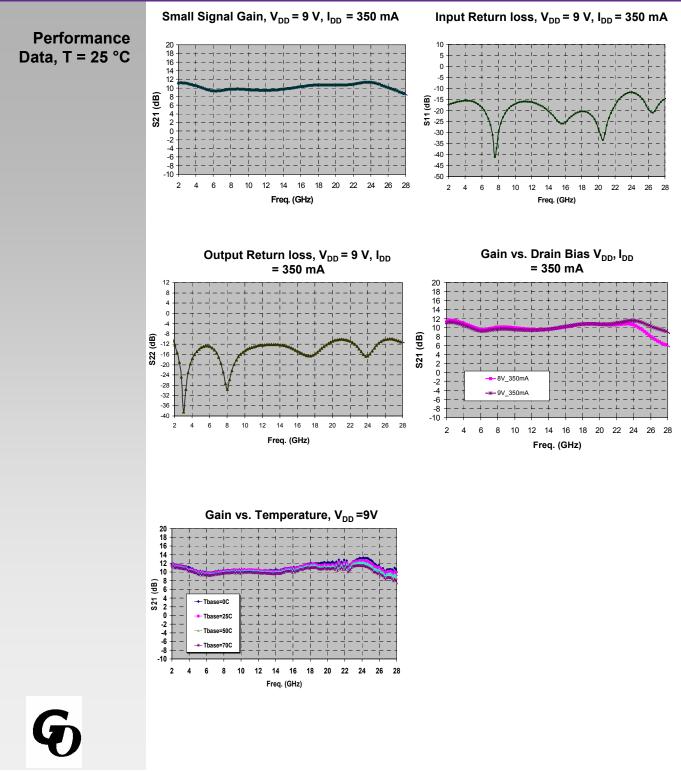


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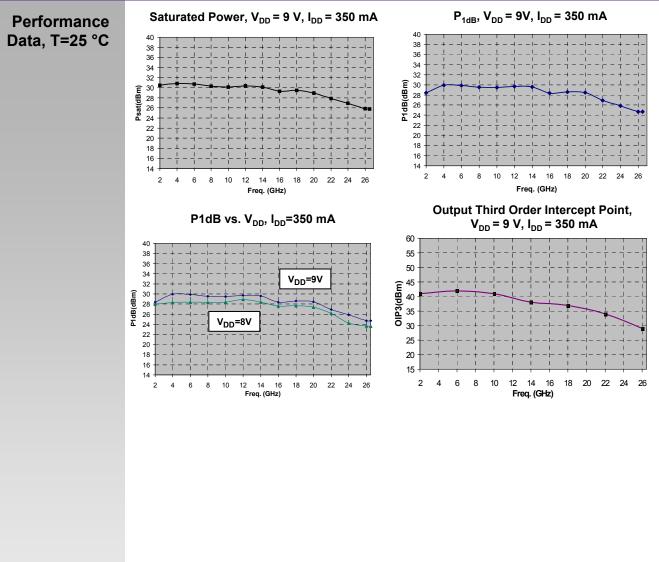
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Thermal Characteristics	SymbolParameters/conditionsRth_jb (°C/W)Tch (°C)MTFF (h)Rth_jbThermal resistance junction-back side of die No RF: DC bias $V_{DD} = 9 V$ , $I_{DQ} = 35 \text{ 0mA}$ , $P_{DC} = 3.1 \text{ W}$ Tbase = 70 C98.5>> +1E7Rth_jbThermal resistance junction-back side of die RF applied: Saturated power 1 W, $V_{DD} = 9 V$ , Pdiss = 4.4 W 
Chip Layout and Bond Pad Locations (Back of chip is RF and DC ground)	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$
G	Chip size tolerance: $\pm 20 \ \mu\text{m}$ Chip thickness: 4 mil with a tolerance of $\pm 0.4 \text{ mil}$ . <b>Pinout and pad dimensions:</b> P1: RF input (100 x 150 $\mu$ m <sup>2</sup> ) P2: V <sub>GG1</sub> , negative voltage (100 x 100 $\mu$ m <sup>2</sup> ) P3: Gate low-frequency extension (250 x 100 $\mu$ m <sup>2</sup> ) P4: RF output and Vdd bias (option 2) by means of bias-tee (100 x 150 $\mu$ m <sup>2</sup> ) P5: Drain low-frequency extension (300 x 100 $\mu$ m <sup>2</sup> ) P6: V <sub>DD</sub> positive voltage (option 1) by means of choke (200 x 100 $\mu$ m <sup>2</sup> ) Note: All dimensions are in millimeters



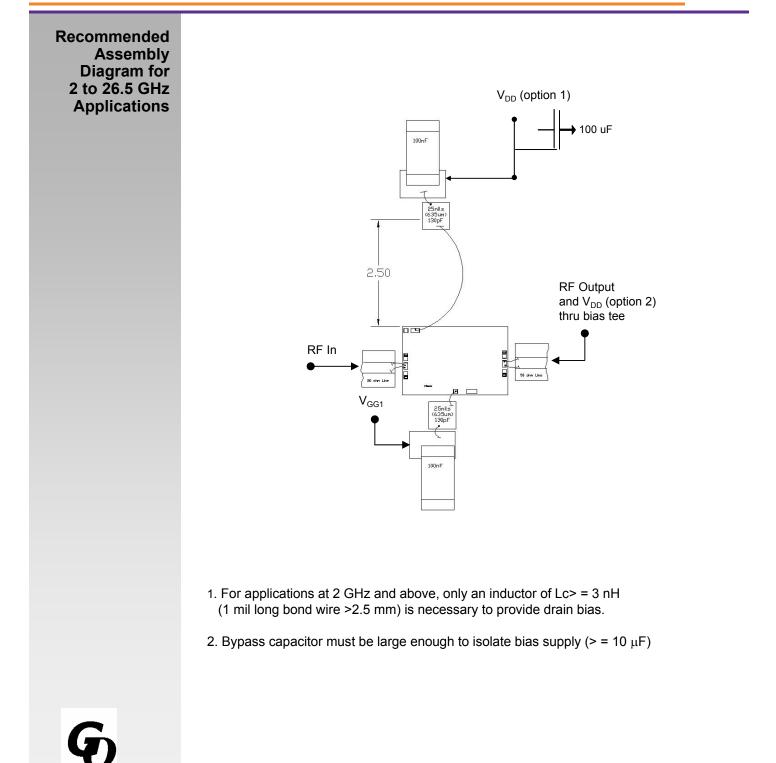




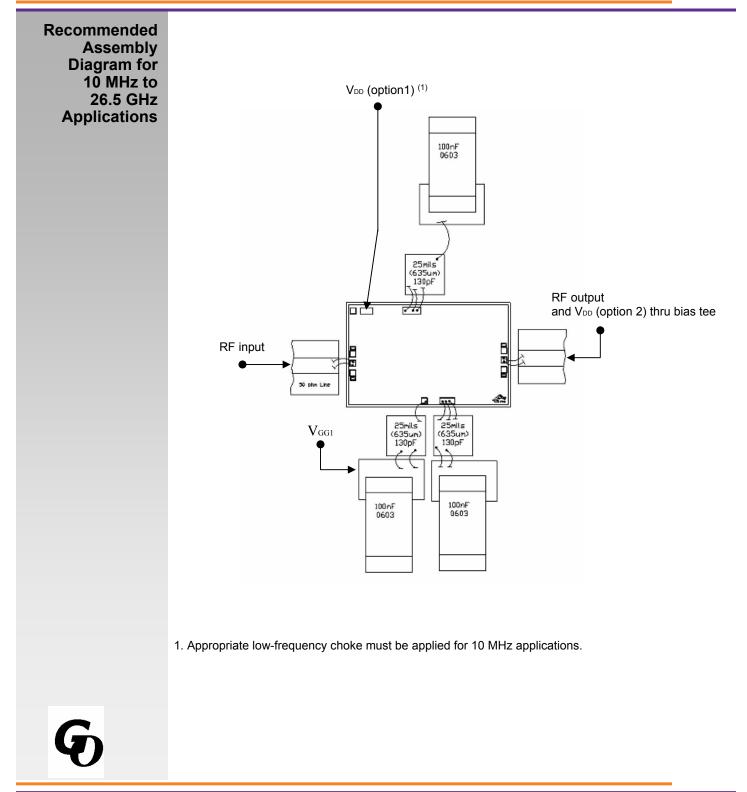














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Recommended Procedure for Biasing and Operation	CAUTION: LOSS OF GATE VOLTAGE ( $V_{GG1}$ and $V_{GG2}$ ) WHILE CORRESPONDING DRAIN VOLTAGE ( $V_{DD}$ ) IS PRESENT CAN DAMAGE THE AMPLIFIER. The following procedure must be considered to properly test the amplifier. The iT2008 amplifier is biased with a positive drain supply ( $V_{DD}$ ) and one negative gate supply ( $V_{GG1}$ ). The recommended bias conditions for the iT2008 is $V_{DD} = 9.0 \text{ V}$ , $I_{DD} = 350$ mA. To achieve this drain current level, $V_{GG1}$ is typically biased between $-0.7\text{V}$ and $-0.9 \text{ V}$ . The gate voltage ( $V_{GG1}$ ) MUST be applied prior to the drain voltage ( $V_{DD}$ ) during power up and removed after the drain voltage is removed during the power down. Drain bias $V_{DD}$ can be applied to the drain (P6). Alternatively, the positive power supply can be applied through an external bias tee to the RF Output pad (P4) .
Low Frequency Operation	External coupling capacitors are needed at the RF_IN (P1) and RF_OUT (P4) ports. The auxiliary gate pad (P3) and drain pad (P5) are provided to extend performance below 2 GHz. Connect these pads via large external capacitors to ground to maintain input and output VSWR at low frequencies. Do not apply bias to these pads. Two options are allowed to provide the positive drain voltage V <sub>DD</sub> . <b>Option 1</b> uses an on-chip pad (P6) where an appropriate value of inductance (choke) must be used to maintain good matching over bandwidth, as reported in the assembly diagram. <b>Option 2</b> uses an external bias-tee directly from the pad at the RF output. For application as low as 10 MHz a large value of inductance must be used in parallel with appropriate resistors in order to optimize gain flatness.
Application Information	<ul> <li>CAUTION: THIS IS AN ESD SENSITIVE DEVICE</li> <li>Chip carrier material should be selected to have GaAs-compatible thermal coefficient of expansion and high thermal conductivity such as copper molybdenum or copper tungsten. The chip carrier should be machined, finished flat, plated with gold over nickel and should be capable of withstanding 325° C for 15 min.</li> <li>Die attachment for power devices should utilize gold/tin (80/20) eutectic alloy solder and should avoid hydrogen environment for PHEMT devices. Note that the back side of the chip is gold plated and is used as RF and DC ground.</li> <li>These GaAs devices should be handled with care and stored in dry nitrogen environment to prevent contamination of bonding surfaces. These are ESD sensitive devices and should be handled with appropriate precaution including the use of wrist-grounding straps. All die attach and wire/ribbon bond equipment must be well grounded to prevent static discharges through the device.</li> <li>Recommended wire bonding uses 3-mil-wide and 0.5-mil-thick gold ribbon with lengths as short as practical allowing for appropriate stress relief. The RF input and output bonds should be typically 12 mil long corresponding to a typical 2 mil gap between the chip and the substrate material.</li> </ul>

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